

NCEP40T11AG-VB Datasheet N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R_{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)		
40	0.0025 at V _{GS} = 10 V	120	38 nC		
	0.0028 at V _{GS} = 6.5 V	105	30 110		

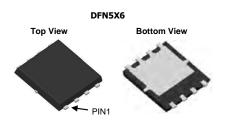
FEATURES

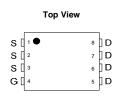
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET[®] Power MOSFET
- 100 % R_g Tested •
- 100 % UIS Tested •

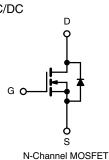
APPLICATIONS

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- Synchronous Rectification
- Secondary Side DC/DC







Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	40	V	
Gate-Source Voltage		V _{GS}	± 20	v	
Continuous Drain Current (T _J = 150 °C)	$T_{C} = 25 \text{ °C}$ $T_{C} = 70 \text{ °C}$ $T_{A} = 25 \text{ °C}$	I _D	120 80 33 ^{b, c}		
$T_{A} = 70 \ ^{\circ}C$ Pulsed Drain Current		I _{DM}	26 ^{b, c} 360	A	
Continuous Source-Drain Diode Current	T _C = 25 °C T _A = 25 °C	I _S	100 4.9 ^{b, c}	\neg	
Single Pulse Avalanche Current		I _{AS}	40		
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	80	mJ	
Maximum Power Dissipation	$T_{C} = 25 \text{ °C}$ $T_{C} = 70 \text{ °C}$ $T_{A} = 25 \text{ °C}$ $T_{A} = 70 \text{ °C}$	P _D	83 53 5.4 ^{b, c} 3.4 ^{b, c}	w	
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Temperature	_	260			

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	18	23	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.0	1.5	0/11		

Notes:

a. Based on T_C = 25 °C.
b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

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d. Maximum under steady state conditions is 90 °C/W.

e. Calculated based on maximum junction temperature. Package limitation current is 80 A.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			43		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	2.0		4.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
		V _{DS} = 40 V, V _{GS} = 0 V			1	μA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 ^{\circ}\text{C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	100			А	
_		V _{GS} = 10 V, I _D = 20 A		0.0025			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} =6.5 V, I _D = 20 A		0.0028		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		102		S	
Dynamic ^b	-	-					
Input Capacitance	C _{iss}			4750			
Output Capacitance	C _{oss}	V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHz		610		pF	
Reverse Transfer Capacitance	C _{rss}			275			
		$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$		78	117	nC	
Total Gate Charge	Qg			38	57		
Gate-Source Charge	Q _{gs}	$V_{DS} = 20 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$		13			
Gate-Drain Charge	Q _{gd}			11			
Gate Resistance	Rg	f = 1 MHz	0.2	0.7	1.4	Ω	
Turn-On Delay Time	t _{d(on)}			14	25	ns	
Rise Time	t _r	$V_{DD} = 20 \text{ V}, \text{ R}_{1} = 2 \Omega$		9	18		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		41	65		
Fall Time	t _f			9	18		
Turn-On Delay Time	t _{d(on)}			33	42		
Rise Time	t _r	V_{DD} = 20 V, R_L = 2 Ω		22	35		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		42	65		
Fall Time	t _f			13	25		
Drain-Source Body Diode Characteris	tics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C		50		A	
Pulse Diode Forward Current ^a	I _{SM}			60			
Body Diode Voltage	V _{SD}	I _S = 5 A		0.75	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			40	60	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			48	72	nC	
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		24	_		
Reverse Recovery Rise Time	t _b			16		ns	

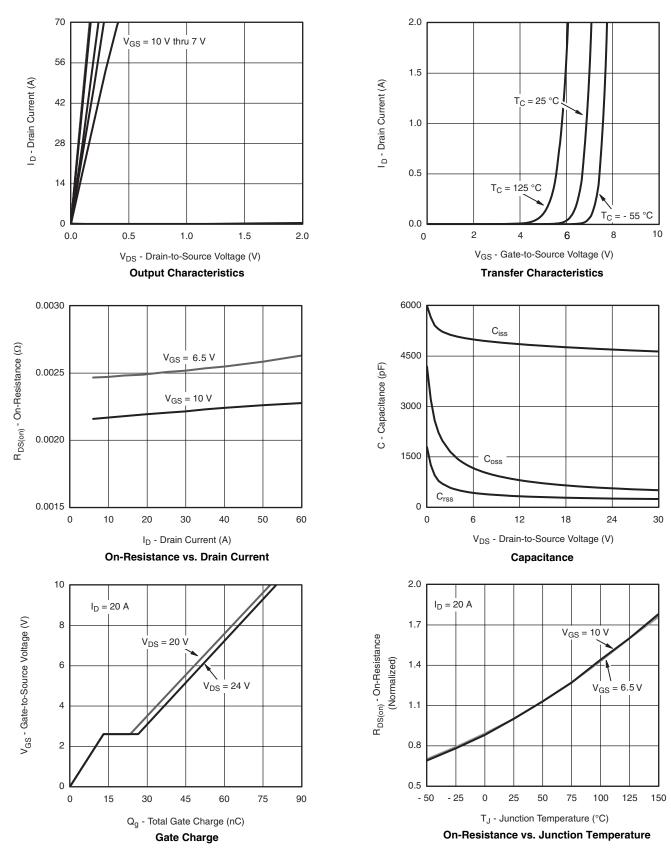
Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

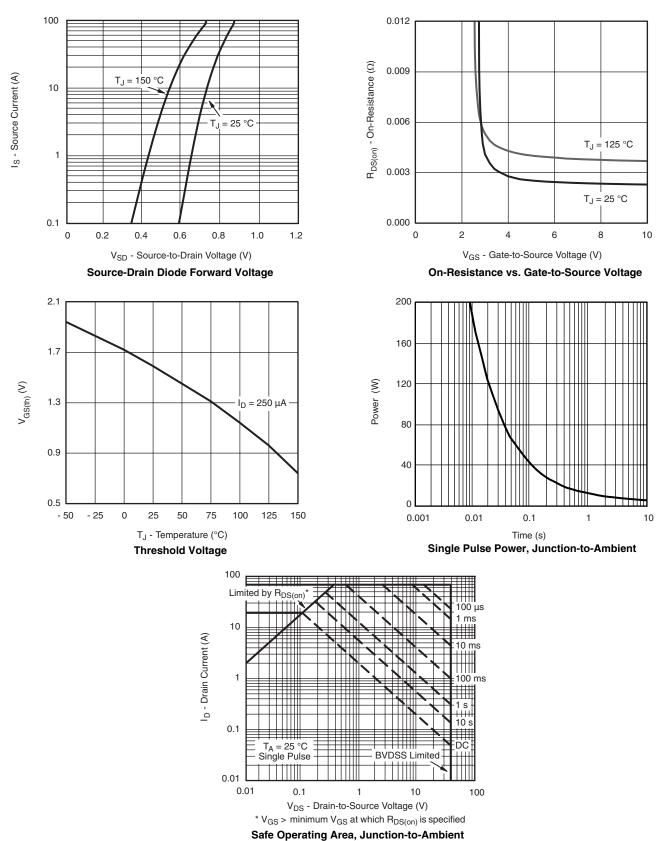
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

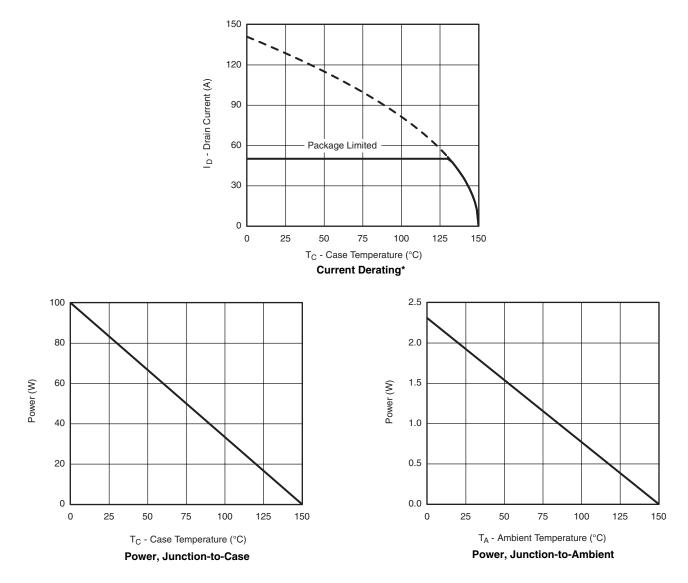






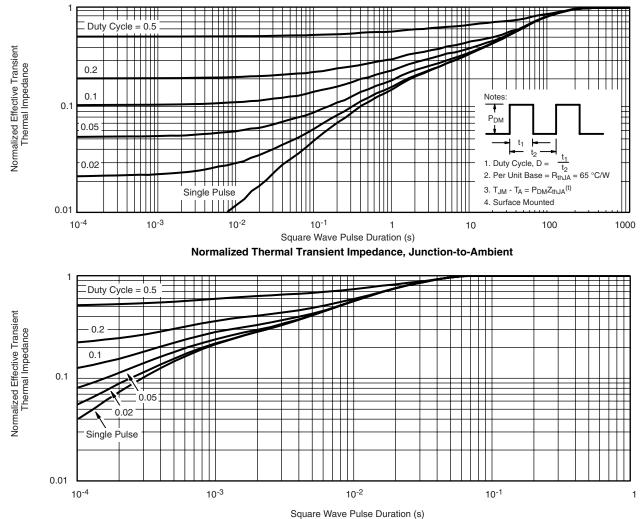






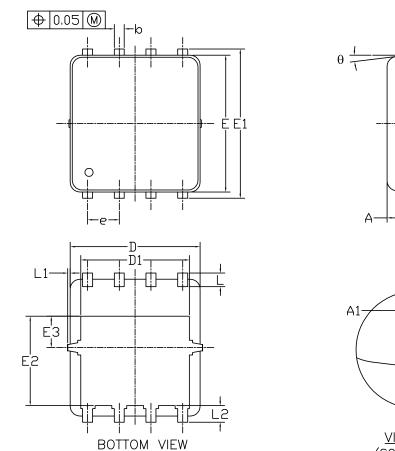
* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



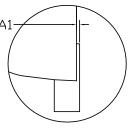


Normalized Thermal Transient Impedance, Junction-to-Case





DFN5x6_8L_EP1_P PACKAGE OUTLIN

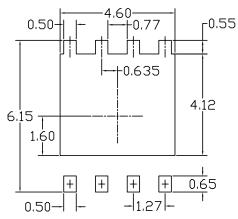


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VIEW 'A'

<u>VIEW 'A'</u> (SCALE 5:1)

RECOMMENDED LAND PATTERN



SYMBOLS	DIMENS	SIONS IN MILLI	METERS	DIMENSIONS IN INCHES			
STMBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
А	0.85	0.95	1.00	0.033	0.037	0.039	
A1	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
с	0.15	0.20	0.25	0.006	0.008	0.010	
D	5.10	5.20	5.30	0.201	0.205	0.209	
D1	4.25	4.35	4.45	0.167	0.171	0.175	
E	5.45	5.55	5.65	0.215	0.219	0.222	
E1	5.95	6.05	6.15	0.234	0.238	0.242	
E2	3.525	3.625	3.725	0.139	0.143	0.147	
E3	1.175	1.275	1.375	0.046	0.050	0.054	
e	1.27 BSC			0.050 BSC			
L	0.45	0.55	0.65	0.018	0.022	0.026	
L1	0		0.15	0		0.006	
L2	0.68 REF			0.027 REF			
θ	0°		10°	0°		10°	

NOTE

 PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
 CONTROLLING DIMENSION IS MILLIMETER.

CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm



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